



PTO/SB/08B (08-03)

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete if Known			
		Application Number	10/687,308		
		Filing Date	10/16/2003		
		First Named Inventor	James E. Millard		
		Art Unit	2621		
		Examiner Name			
Sheet	1	of	1	Attorney Docket Number	6162.004

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
mgd		L. G. Brown, "A Survey of Image Registration Techniques," Columbia University, Computer Science Department Publication, New York, NY, 1991	
		R. C. Gonzalez et al., Digital Image Processing, Addison-Wesley, Reading, MA, 1987 (book, copy not available)	
mgd		J. Schmit et al., "Extended averaging technique for derivation of error-compensating algorithms in phase-shifting interferometry," Applied Optics, Vol. 34, p. 3610, July 1995	
mgd		C. K. Hong et al., "Least-squares fitting of the phase map obtained in phase-shifting electronic speckle pattern interferometry," Optics Letters, Vol. 20, p.931, April 1995	
mgd		T. D. Upton et al., "Optical and electronic design of a calibrated multichannel electronic interferometer for quantitative flow visualization," Appl. Opt., V 34, No. 25, 1995	
		C. Koliopoulos et al., "Simultaneous phase shift interferometer," SPIE Vol. 1531, pp. 119-127, 1991	
mgd		Schwider et al., "Digital wave-front measuring interferometry: some systemic error sources," Applied Optics, Vol. 22, pp. 3421-3432, 1983	
mgd		Schwider et. al., "Phase shifting interferometry: reference phase error reduction," Applied Optics, Vol 28, No. 18, pp. 3889-3892, 1989	
mgd		Schwider et al., "Some considerations of reduction of reference phase error in phase-stepping interferometry," Applied Optics, Vol. 38, No. 4, pp. 655-659, 1999	
mgd		M. F. Kuchel, "Advanced Interferometry at Carl Zeiss," Proceedings of SPIE, Vol. 1720, p 452-456 (1992)	

Examiner Signature	<i>Maurice J. Detoch</i>	Date Considered	8/18/05
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Substitute for form 1449/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	
		Filing Date	
		First Named Inventor	James E. Millerd
		Art Unit	
		Examiner Name	
Sheet 1 of 2	Attorney Docket Number	6162.004	

U. S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
mjd		US- 4,575,248	03/11/1986	Horwitz et al.	
mjd		US- 4,624,569	11/25/1986	Kwon	
mjd		US- 5,589,938	12/31/1996	Deck	
mjd		US- 5,663,793	09/02/1997	de Groot	
mjd		US- 5,777,741	07/07/1998	Deck	
mjd		US- 5,883,717	03/16/1999	DiMarzio et al.	
mjd		US- 5,926,283	07/20/1999	Hopkins	
mjd		US- 5,982,497	11/09/1999	Hopkins	
mjd		US- 6,304,330 B1	10/16/2001	Millerd et al.	
mjd		US- 6,249,289 B1	06/19/2001	Arnaud et al.	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁵
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Examiner Signature	<i>Maurice J. Detsch</i>	Date Considered	8/18/05
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		Filing Date	
		First Named Inventor	James E. Millerd
		Art Unit	
		Examiner Name	
Sheet 2 of 2	Attorney Docket Number	6162.004	

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mgd		L. G. Brown, "A Survey of Image Registration Techniques," Columbia University, Computer Science Department Publication, New York, NY, 1991	
mgd		R. C. Gonzalez et al., Digital Image Processing, Addison-Wesley, Reading, MA, 1987	
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mgd		T. D. Upton et al., "Optical and electronic design of a calibrated multichannel electronic interferometer for quantitative flow visualization," Appl. Opt., Vol. 34, No. 25, 19	
mgd		C. Koliopoulos et al., "Simultaneous phase shift interferometer," SPIE Vol. 1531, pp. 119-127, 1991	
mgd		Schwider et al., Applied Optics, Vol. 22, pp. 3421-3432, 1983)	
mgd		Schmit et. al., Applied Optics Vol. 34, pp. 3610-3619, 1995	
mgd		M. F. Kuchel, "Advanced Interferometry at Carl Zeiss," Proceedings of SPIE, Vol. 1720, p.452-456 (1992)	

Examiner Signature	Marissa J. Delsch	Date Considered	8-28-05
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